Search Notes

	Application/Control No.	Applicant(s)/Patent under Reexamination	
Į	10/807,097	OPHARDT, HEI	NER
	Examiner	Art Unit	
	Frederick C. Nicolas	3754	

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222	94-95,104	10/12/2006	FN		
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222	105,107	10/12/2006	FN		
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222	104	10/12/2006	FN	
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222	99	10/12/2006	FN	
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SEARCH NO (INCLUDING SEARC)
	DATE	EXMR
East and text search including inventor's name search. Interference search also conducted.	10/12/2006	FN